


<b>Search Notes</b> 	<b>Application/Control No.</b> 10587268	<b>Applicant(s)/Patent Under Reexamination</b> TAKAIWA ET AL.
	<b>Examiner</b> Michael Liu	<b>Art Unit</b> 2851

SEARCHED			
Class	Subclass	Date	Examiner
355	30, 53, 55, 67	6/11/08	ML

SEARCH NOTES		
Search Notes	Date	Examiner
See EAST search history printout.	6/11/08	ML
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INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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